

N-Channel 30 V (D-S) MOSFET

PRODUCT SUMMARY					
V _{DS} (V)	$R_{DS(on)}(\Omega)$	I _D (A) ^{a, e}	Q _g (Typ.)		
30	0.0039 at V _{GS} = 10 V	80	71 nC		
30	0.005 at $V_{GS} = 4.5 \text{ V}$	70	71110		

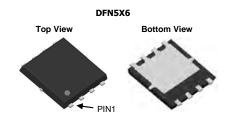
FEATURES

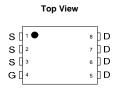
- DT-Trench Power MOSFET
- 100 % R_g and UIS Tested

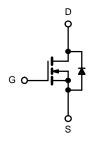


APPLICATIONS

- · Notebook PC Core
- VRM/POL







N-Channel MOSFET

ABSOLUTE MAXIMUM RATING	S (T _A = 25 °C, unle	ess otherwise n	oted)		
Parameter	Symbol	Limit	Unit		
Drain-Source Voltage	V_{DS}	30	V		
Gate-Source Voltage		V_{GS}			± 20
	T _C = 25 °C		80 ^{a, e}		
Continuous Drain Current (T _{.I} = 175 °C)	T _C = 70 °C	I _D	70 ^e		
Continuous Diam Current (1) = 173 C)	T _A = 25 °C	'D	21 ^{b, c}	A	
	T _A = 70 °C		20.8 ^{b, c}		
Pulsed Drain Current		I _{DM}	240		
Avalanche Current Pulse		I _{AS}	26		
Single Pulse Avalanche Energy	L = 0.1 mH	E _{AS}	53.2	mJ	
Continuous Source-Drain Diode Current	T _C = 25 °C	Is	80 ^{a, e}	A	
Continuous Source-Drain Diode Current	T _A = 25 °C	'S	2.76 ^{b, c}		
	T _C = 25 °C		210 ^a		
Manianum Bauran Dinain atian	T _C = 70 °C	P _D	155	\exists w	
Maximum Power Dissipation	T _A = 25 °C	םים	3.35 ^{b, c}		
	T _A = 70 °C		2.13 ^{b, c}		
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to 175	°C	

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient ^{b, d}	t ≤ 10 s	R _{thJA}	41	50	°C/W	
Maximum Junction-to-Case	Steady State	R _{thJC}	0.7	0.9	C/VV	

Notes:

- a. Based on T_C = 25 °C. b. Surface mounted on 1" x 1" FR4 board.
- d. Maximum under steady state conditions is 90 °C/W.
- e. Calculated based on maximum junction temperature. Package limitation current is 80 A.



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Parameter	Symbol	Test Conditions	Min .	Тур.	Max.	Unit	
Static			•				
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	30			V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I _D = 250 μA		35		m\//°C	
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_{J}$	ι _D = 230 μΑ		- 5.5		mV/°C	
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	1		3	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA	
Zara Cata Valtaga Drain Current	I _{DSS}	V _{DS} = 30 V, V _{GS} = 0 V			1	μA	
Zero Gate Voltage Drain Current		V _{DS} = 30 V, V _{GS} = 0 V, T _J = 55 °C			10		
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	80			Α	
D : 0	В	V _{GS} = 10 V, I _D = 32 A		0.0039	0.0043	Ω	
Drain-Source On-State Resistance ^a	R _{DS(on)}	$V_{GS} = 4.5 \text{ V}, I_D = 29 \text{ A}$		0.005	0.006		
Forward Transconductance ^a	9 _{fs}	$V_{DS} = 15 \text{ V}, I_D = 32 \text{ A}$		130		S	
Dynamic ^b							
Input Capacitance	C _{iss}			1590		pF	
Output Capacitance	C _{oss}	$V_{DS} = 12.5 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		1025			
Reverse Transfer Capacitance	C _{rss}			970			
Total Gate Charge	Qg	V _{DS} = 15 V, V _{GS} = 10 V, I _D = 32 A		71			
				61.5		nC	
Gate-Source Charge	Q_{gs}	$V_{DS} = 15 \text{ V}, V_{GS} = 4.5 \text{ V}, I_{D} = 29 \text{ A}$		34			
Gate-Drain Charge	Q_{gd}			29			
Gate Resistance	R_g	f = 1 MHz		1.4	2.1	Ω	
Turn-On Delay Time	t _{d(on)}			18	27		
Rise Time	t _r	V_{DD} = 15 V, R_L = 0.555 Ω		11	17		
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 27 \text{ A}, V_{GEN} = 10 \text{ V}, R_g = 1 \Omega$		70	105		
Fall Time	t _f			10	15	20	
Turn-On Delay Time	t _{d(on)}			55	83	ns	
Rise Time	t _r	V_{DD} = 15 V, R_L = 0.625 Ω		180	270		
Turn-Off Delay Time	t _{d(off)}	$I_D\cong 24$ A, $V_{GEN}=4.5$ V, $R_g=1$ Ω		55	83		
Fall Time	t _f			12	18		
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	I _S	$T_C = 25 ^{\circ}C$			80	Δ	
Pulse Diode Forward Current ^a	I _{SM}				240	Α	
Body Diode Voltage	V _{SD}	I _S = 22 A		0.8	1.2	V	
Body Diode Reverse Recovery Time	t _{rr}			52	78	ns	
Body Diode Reverse Recovery Charge	Q _{rr}	I _F = 20 A, di/dt = 100 A/µs, T _{.I} = 25 °C		70.2	105	nC	
Reverse Recovery Fall Time t _a		1 _F = 20 Λ, απαι = 100 Λ/μο, 1 _J = 25 °C		27		ns	
Reverse Recovery Rise Time	t _b	t _b		25			

Notes:

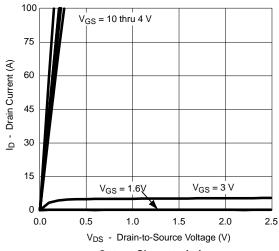
- a. Pulse test; pulse width $\leq 300~\mu s,$ duty cycle $\leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.



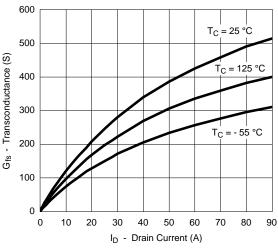
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TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

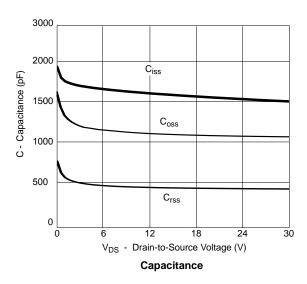


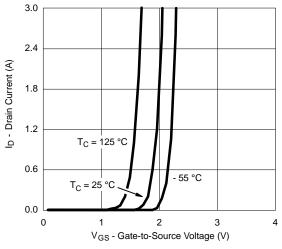
Din-Tek SEMICONDUCTOR

Output Characteristics

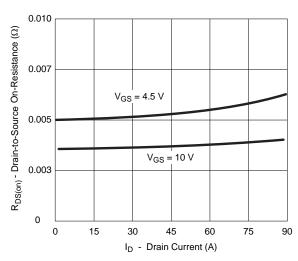


Transconductance

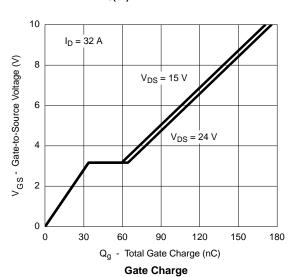




Transfer Characteristics

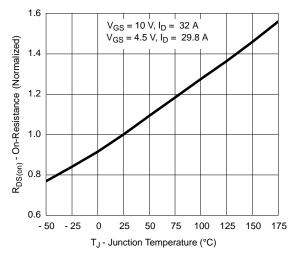


R_{DS(on)} vs. Drain Current

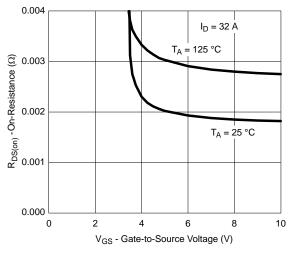




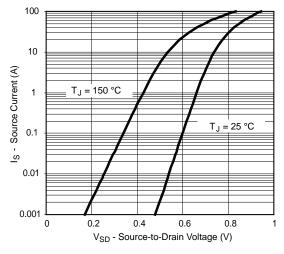
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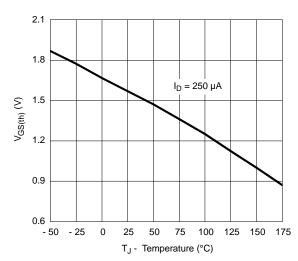
On-Resistance vs. Junction Temperature



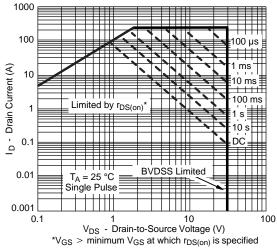
 $R_{DS(on)}$ vs. V_{GS} vs. Temperature



Forward Diode Voltage vs. Temperature



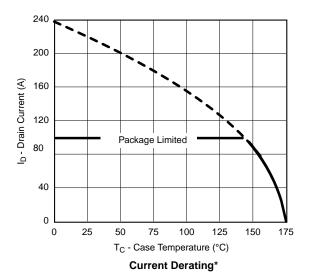
Threshold Voltage

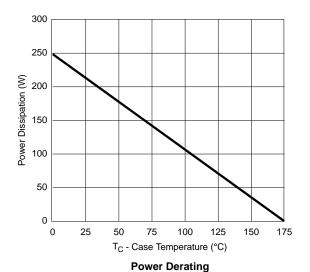


Safe Operating Area, Junction-to-Ambient

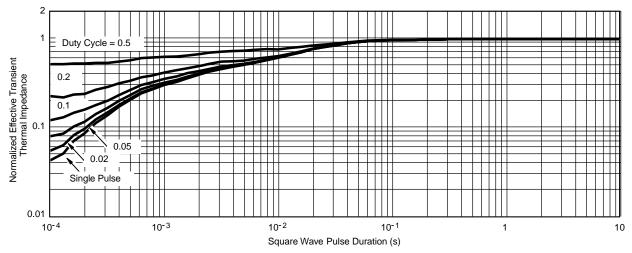








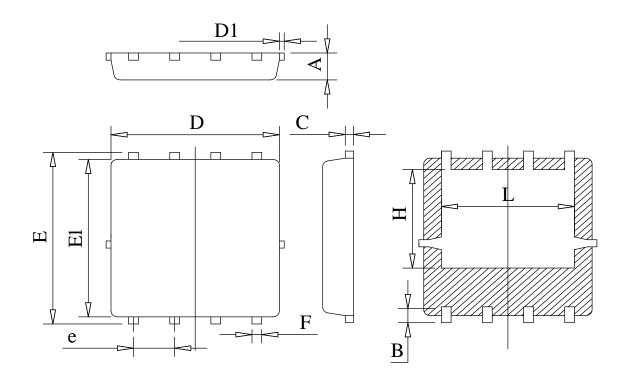
* The power dissipation P_D is based on $T_{J(max)} = 175$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.



Normalized Thermal Transient Impedance, Junction-to-Case



DFN5X6-8L PACKAGE OUTLINE



COMMON DIMENSIONS (UNITS OF MEASURE=MILLIMETER)

Unit: mm

Symbol	Min	Тур	Max
A	0.78	0.95	1.12
В	0.45	0.58	0.78
С	0.18	0.254	0.36
D	4.70	5.20	5.45
D1			0.18
Е	5.85	6.05	6.25
E1	5.38	5.55	5.98
e	1.15	1.27	1.40
F	0.18	0.30	0.52
Н	3.25	3.47	3.70
L	3.75	4.00	4.25





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